

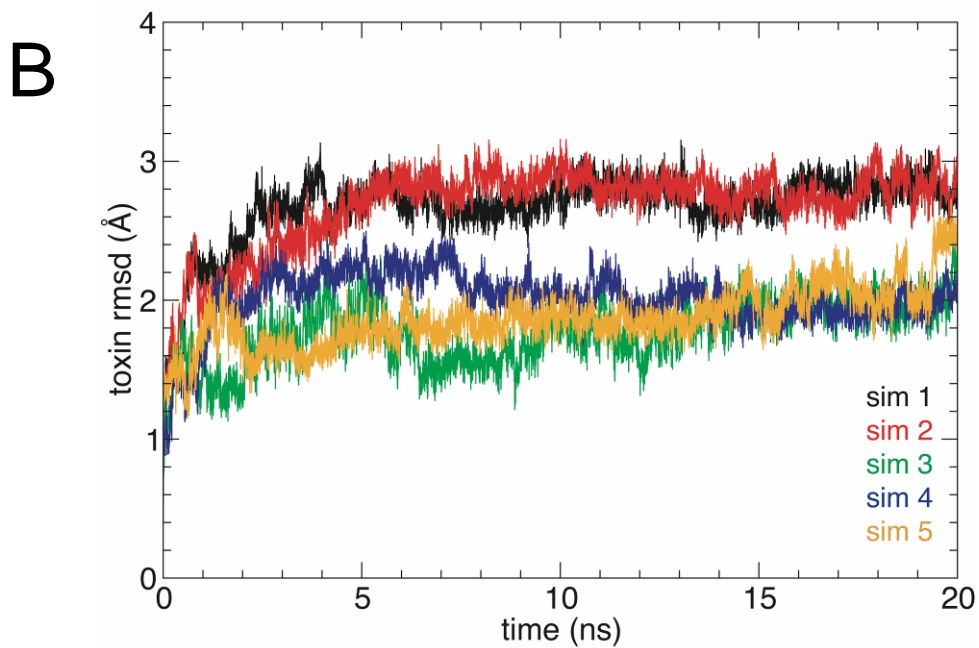
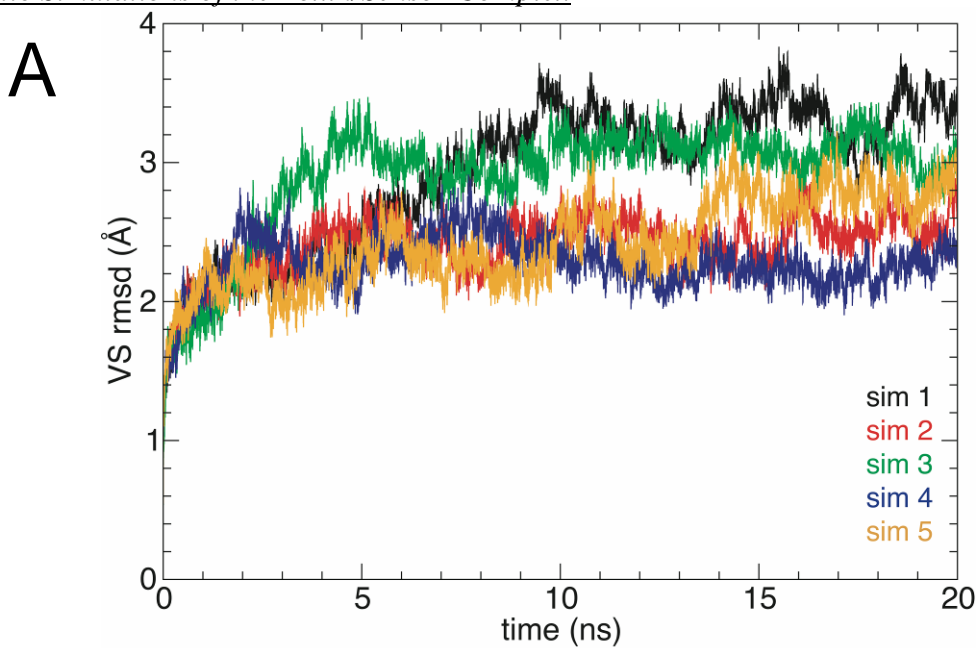
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Supporting Material

Interactions Between a Voltage Sensor and a Toxin via Multi-Scale Simulations

Chze Ling Wee, David Gavaghan, and Mark Sansom

Atomistic Simulations of the Toxin/Sensor Complex



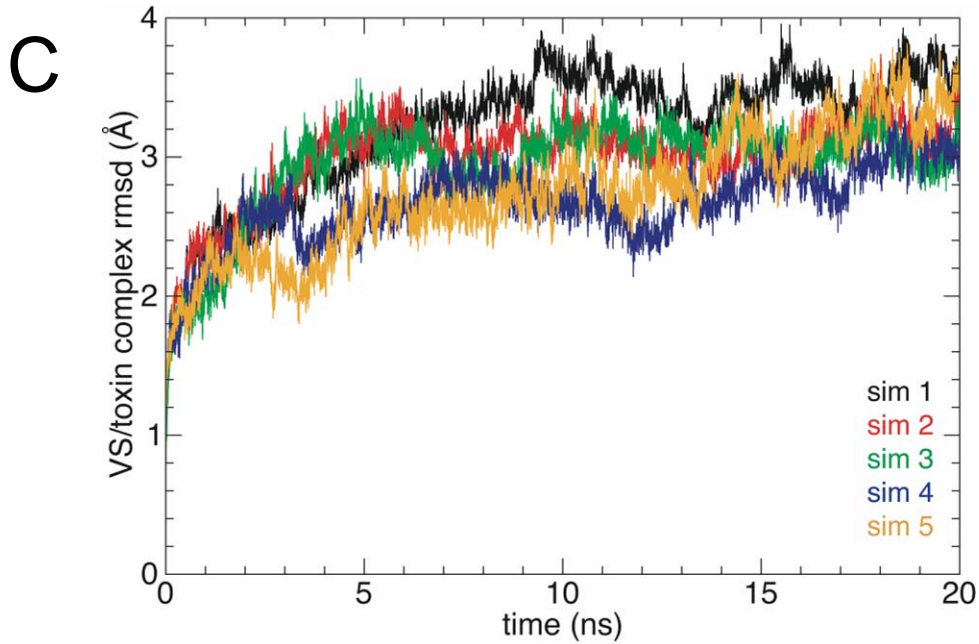


Fig. S1: Root-mean-squared-deviation (RMSD) of the C α atoms of (A) VS, (B) toxin, and (C) VS/toxin complex in the AT simulations (after a C α least-squared-fit to the initial (i.e. 0 ns) structure).

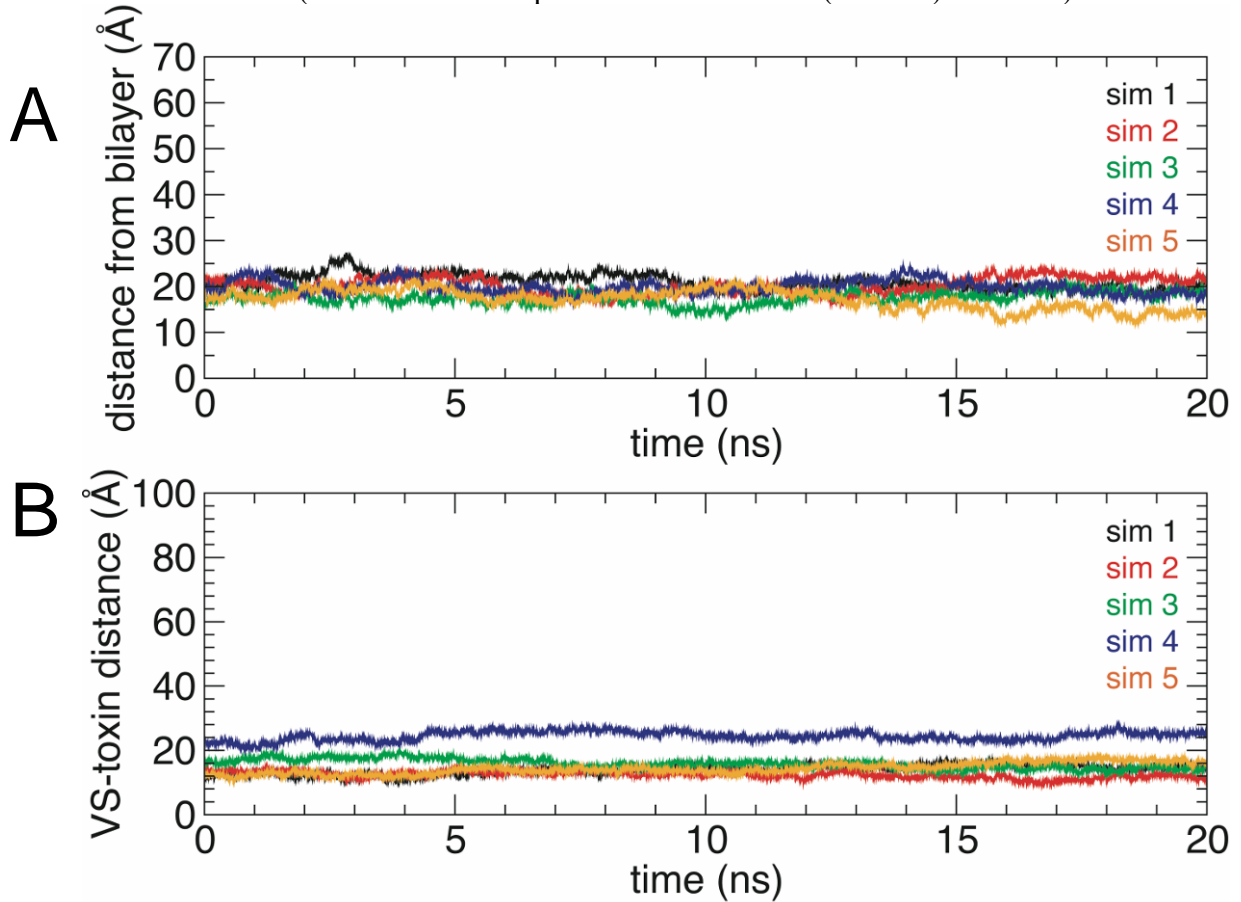


Fig. S2: (A) Distance between the COMs of VSTx1 and the POPC bilayer projected along the bilayer normal in the AT simulations. (B) Distance between the COMs of VSTx1 and VS projected along the plane of the membrane surface in the AT simulations.

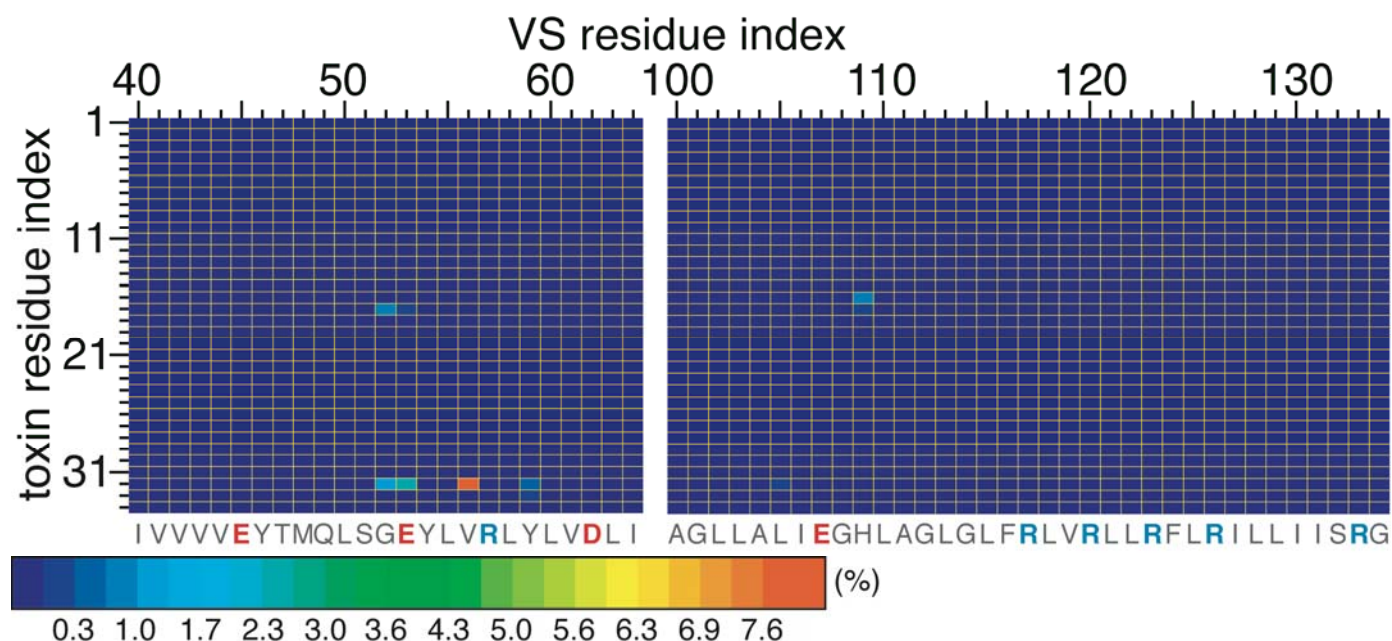
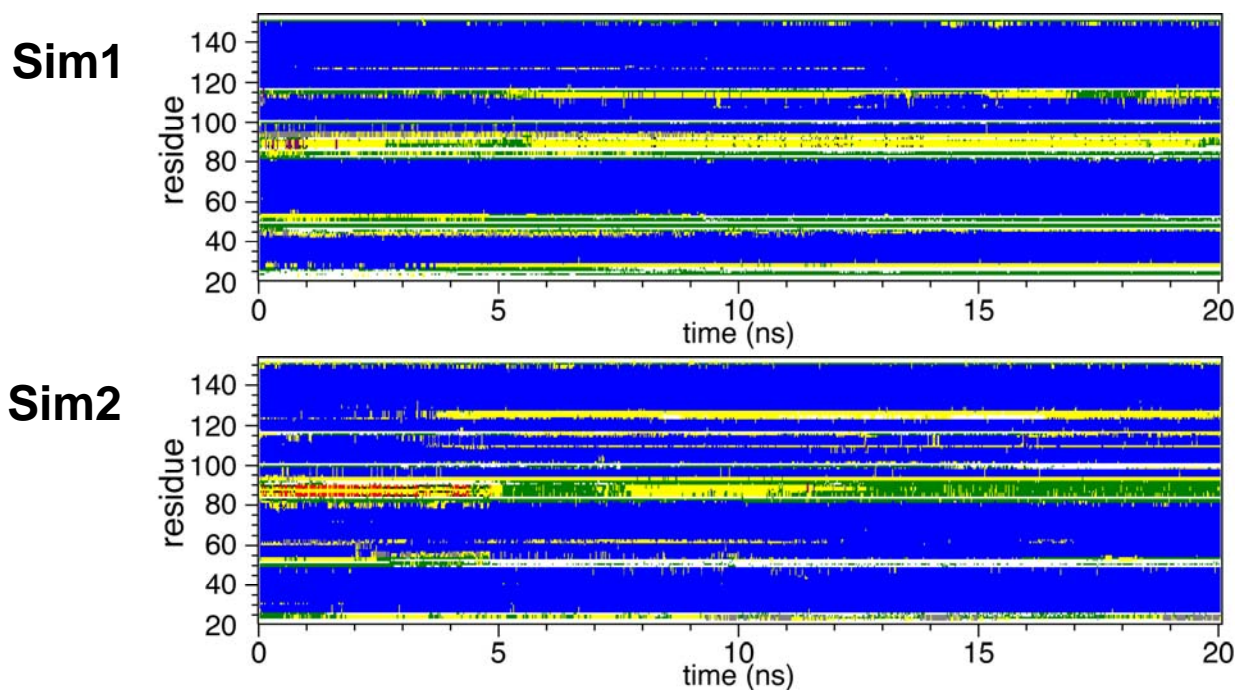
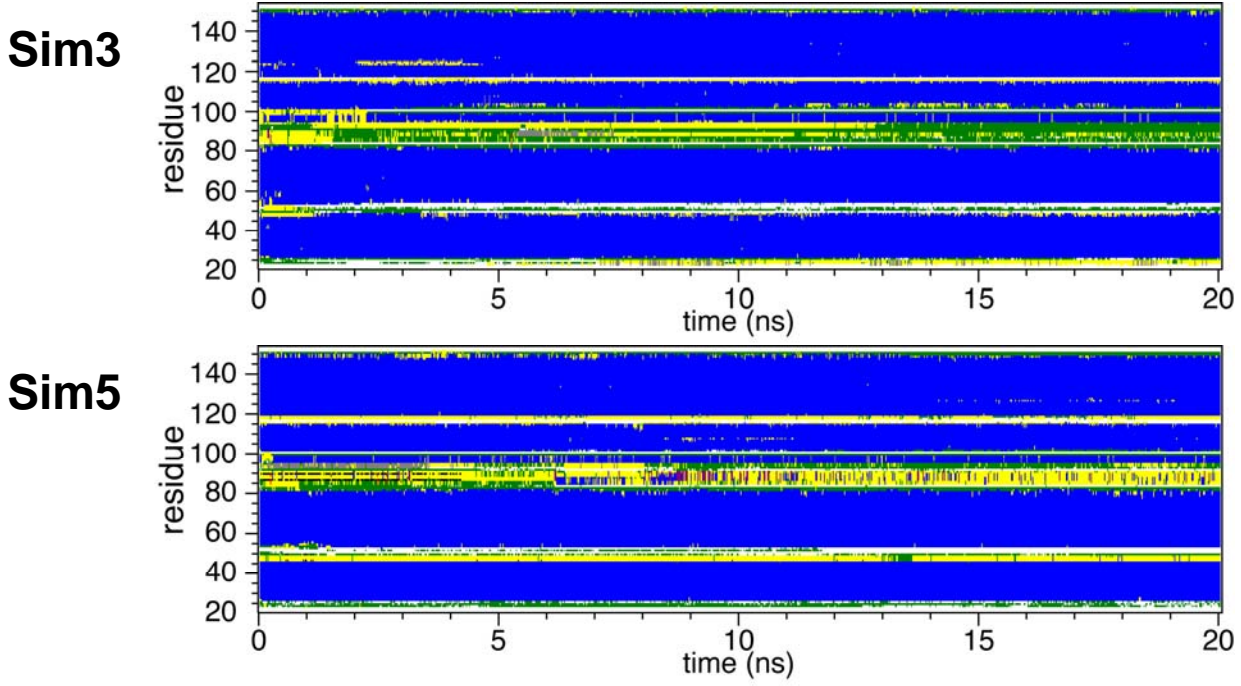


Fig. S3: Analyses of the VS/toxin interface in AT Simulation 4. Frequency of contacts (expressed as a percentage) between VS and toxin residues over 10 to 20 ns. A distance cut-off of 3.5 Å was used to define a contact. Basic and acidic residues are labelled in blue and red respectively.





Coil
 B-Bridge
 Bend
 Turn
 A-Helix
 5-Helix
 3-Helix

Fig S4: Time evolution of the secondary structure of the VS in AT Simulations 1, 2, 3 and 5.